

Session Program

27 September 2026 to 2 October 2026

GADEST 2026

Defect Engineering and Metrology

GADEST 2026 - San Servolo Island, Venice (Italy)

Sunday 27 September

17:00

Defect Engineering and Metrology

Session | Location: Theatre Hall

17:00-17:40

Scanning Spreading Resistance Microscopy as a Key Nano-Metrology Technique for Semiconductor Technology Scaling - History and Future

Speaker

Lennaert Wouters

17:40-18:20

Defect mitigation strategies for next-generation, high-efficiency silicon-based solar cells

Speaker

Dr Lachlan Black

18:20